

M3253503E2A473KZMB

Aliases (C0603K473K5RML) SMD MIL X7R PRF32535, Ceramic, 0.047 uF, 10%, 50 VDC, X7R, SMD, MIL-PRF-32535, N/A, 0603, 0.5 mm



| General Information | |
|--------------------------|--|
| Series | SMD MIL X7R PRF32535 |
| Style | SMD Chip |
| Description | SMD, MIL-PRF-32535 |
| RoHS | No |
| Prop 65 | WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov / . |
| SCIP Number | d66873f5-e54d-410c-a0cf-ebf 6fcf635b5 |
| Termination | Solder Plated |
| Failure Rate | N/A |
| Qualifications | MIL-PRF-32535 M-Level |
| AEC-Q200 | No |
| Typical Component Weight | 6.3 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|---------------------|
| Chip Size | 0603 |
| L | 1.6mm +0.2/-0.15mm |
| W | 0.81mm +0.2/-0.15mm |
| Т | 1.02mm MAX |
| S | 0.5mm MIN |
| В | 0.41mm +/-0.2mm |
| | |

| Packaging Specifications | |
|--------------------------|--------|
| Packaging | Waffle |
| Packaging Quantity | 100 |

| Specifications | |
|--|---------------------|
| Capacitance | 0.047 uF |
| Tolerance | 10% |
| Voltage DC | 50 VDC |
| Dielectric Withstanding Voltage | 125 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | X7R |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 15%, 1kHz 1.0Vrms |
| Dissipation Factor | 2.5%1kHz1.0Vrms |
| Aging Rate | 3% Loss/Decade Hour |
| Insulation Resistance | 21.2766 GOhms |

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